

Notice of References Cited		Application/Control No. 10/579,732	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
		Examiner JOSEPH DEAN, JR	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0095486 A1	07-2002	Bahl, Paramvir	709/223
*	B	US-2003/0054818 A1	03-2003	Bahl et al.	455/432
*	C	US-2003/0157936 A1	08-2003	Ohtani et al.	455/436
*	D	US-2004/0137901 A1	07-2004	Hamasaki et al.	455/436
*	E	US-2004/0259541 A1	12-2004	Hicks et al.	455/426.1
*	F	US-2004/0242240 A1	12-2004	Lin, Jyh-Han	455/456.3
*	G	US-6,954,442 B2	10-2005	Tsirtsis et al.	370/328
*	H	US-7,113,799 B2	09-2006	Ahmad et al.	455/458
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.